PHD3055E

N-channel TrenchMOS standard level FET

Rev. 07 — 26 February 2010

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics

1.3 Applications

DC-to-DC convertors

■ Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	60	V
I_D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 1</u> and <u>3</u>	-	-	10.3	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	33	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 44 \text{ V}; T_j = 25 \text{ °C};$ see Figure 12	-	3.2	-	nC
Static ch	naracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 5.5 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 10 and 11	-	120	150	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description		Simplified outline	Graphic symbol		
1	G	gate					
2	D	drain	<u>[1]</u>	mb			
3	S	source					
mb	D	mounting base; connected to drain			mbb076 S		
				SOT428 (DPAK)			

^[1] It is not possible to make connection to pin 2

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PHD3055E	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	60	V
V_{DGR}	drain-gate voltage	$T_j \ge 25$ °C; $T_j \le 175$ °C; $R_{GS} = 20$ kΩ	-	60	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	7.3	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 1}}{\text{A}} \text{ and } \frac{3}{\text{C}}$	-	10.3	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	41	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	33	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	10.3	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	41	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 3.3 A; V_{sup} ≤ 25 V; R_{GS} = 50 Ω; unclamped; t_p = 0.22 ms	-	25	mJ
I _{DS(AL)S}	non-repetitive drain-source avalanche current	$V_{GS} = 10 \text{ V}; V_{sup} \le 25 \text{ V}; R_{GS} = 50 \Omega;$ $T_{j(init)} = 25 \text{ °C}; \text{ unclamped}; \text{ see } \frac{\text{Figure 4}}{Constant of the properties of th$	-	10.3	Α

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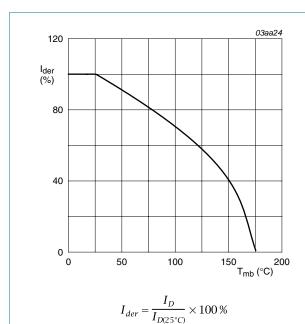
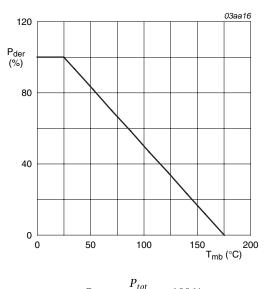
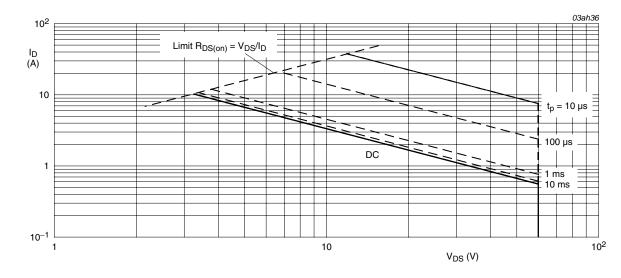


Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

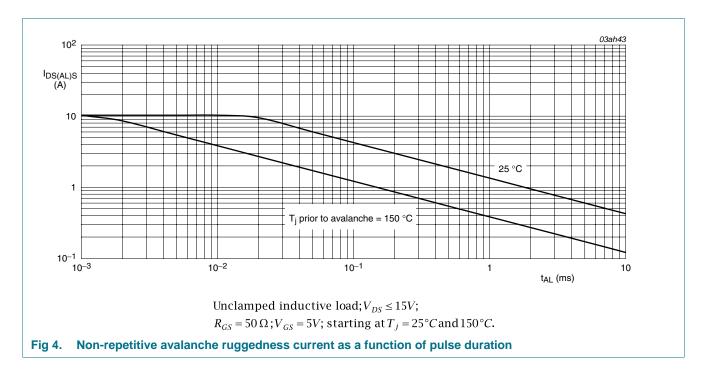
Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

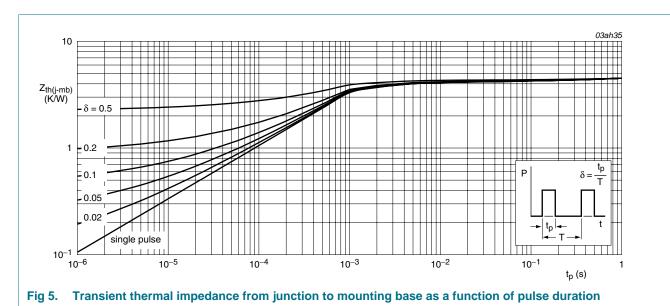
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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 5	-	-	4.5	K/W
uily a)		SOT428 minimum footprint; mounted on a PCB	-	75	-	K/W
	junction to ambient	SOT404minimum footprint; mounted on a PCB	-	50	-	K/W



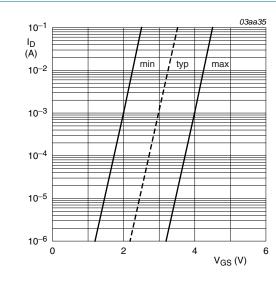
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6. Characteristics

Table 6. Characteristics

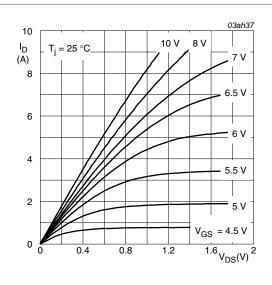
Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
(DIV)DOO	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	55	-	-	V
breakdown voltage		$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	60	-	-	V
V _{GS(th)} gate-source to voltage	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see Figure 9	1	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 9</u>	-	-	6	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 9	2	3	4	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
Doon	drain-source on-state resistance	V _{GS} = 10 V; I _D = 5.5 A; T _j = 175 °C; see <u>Figure 10</u> and <u>11</u>	-	250	315	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 5.5 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 10 and 11	-	120	150	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	5.8	-	nC
Q_{GS}	gate-source charge	$T_j = 25$ °C; see <u>Figure 12</u>	-	1.5	-	nC
Q_{GD}	gate-drain charge		-	3.2	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	190	250	pF
C _{oss}	output capacitance	$T_j = 25$ °C; see <u>Figure 13</u>	-	55	80	pF
C _{rss}	reverse transfer capacitance		-	40	50	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 2.7 \Omega; V_{GS} = 10 \text{ V};$	-	3	10	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega; T_j = 25 \text{ °C}$	-	26	35	ns
d(off)	turn-off delay time		-	8	15	ns
t _f	fall time		-	10	20	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 10 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 14	-	1.1	1.5	V
t _{rr}	reverse recovery time	$I_S = 10 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	32	-	ns
Q _r	recovered charge	$V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$	-	50	-	nC

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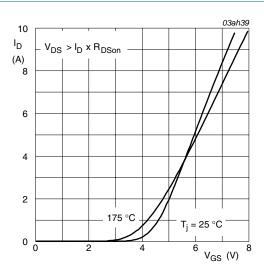
 $T_j=25\,^{\circ}C; V_{DS}=5V$

Fig 6. Sub-threshold drain current as a function of gate-source voltage



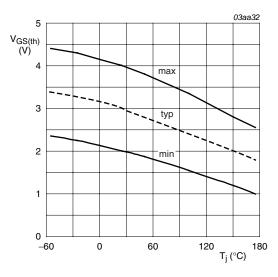
 $T_j = 25^{\circ}C$

Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature

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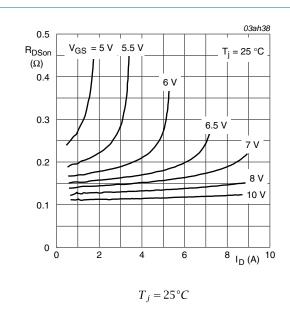


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

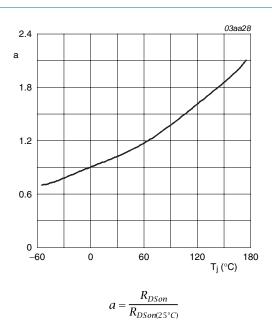
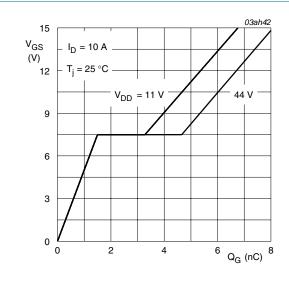


Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature



 $I_{D}=10A; V_{DD}=11V \, {\rm and} \, 44V$ Fig 12. Gate-source voltage as a function of gate

charge; typical values

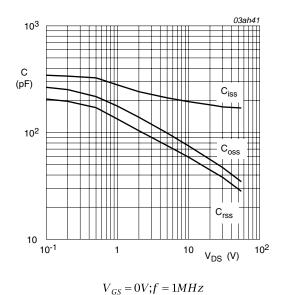


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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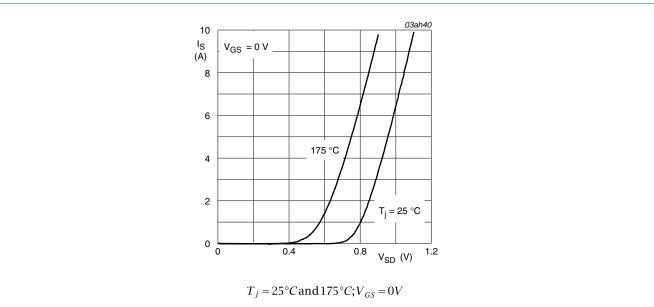


Fig 14. Source current as a function of source-drain voltage; typical values

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7. Package outline

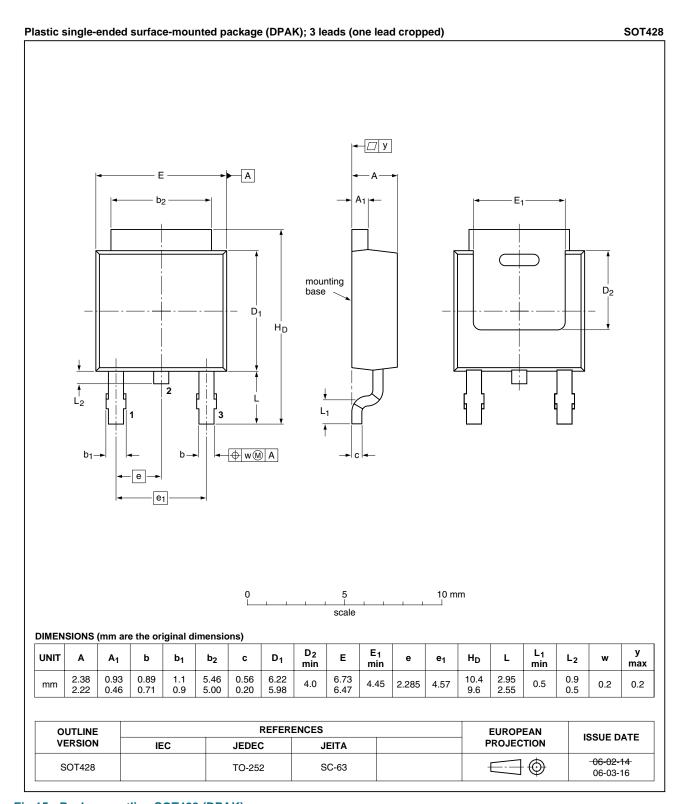


Fig 15. Package outline SOT428 (DPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHD3055E_7	20100226	Product data sheet	-	PHP_PHD3055E-06
Modifications: • The format of guidelines of Legal texts h		of this data sheet has be of NXP Semiconductors. have been adapted to the or PHD3055E separated to	e new company name w	nere appropriate.
PHP_PHD3055E-06 (9397 750 09354)	20020325	Product data	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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